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DEM1P010	10/092,361
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U.S. PATENT DOCUMENTS

EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SAB	AA	6,725,208	04/20/2004	Hartman et al.			

OTHER DOCUMENTS (*Including Author, Title, Date, Pertinent Pages, Etc.*)

SAB	BA		A.F.M. Smith, "A General Bayesian Linear Model," University of Oxford, April 1972.

EXAMINER: [signature] DATE CONSIDERED 11/03/2007

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EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
JRB	AA	6,684,193	01/27/2004	Chavez et al.			
JRB	AB	6,553,352	04/22/2003	Delurgio et al.			
JRB	AC	6,044,357	03/28/2000	Garg			

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	11/03/2004

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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	TRANSLATION YES	TRANSLATION NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

IB	AA	"Merriam Webster's Collegiate Dictionary", 10th edition, pg 585, Merriam-Webster Incorporated, 1999.
IB	AB	Hernandez, Mauricio A., and Salvatore J. Stolfo, "Real-world Data is Dirty: Data Cleansing and the Merge/Purge Problem", Data Mining and Knowledge Discovery, Vol. 2, Issue 1, January 1998.

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EXAMINER INITIAL*		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
DR	AA	6,567,824	05/20/03	Fox			
DR	AB	6,321,207	11/20/01	Ye			

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